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**Measuring methods for semiconductor photodiode and
phototransistor**

半导体光电二极管和光电晶体管测试方法

(English Translation)

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What this standard covers

This Standard specifies the test method for a semiconductor photodiode and a phototransistor (hereinafter referred to as "devices") of optical parameters. This Standard applies to testing semiconductor photodiode and phototransistor photoelectric parameters. This Standard is not applicable PIN, avalanche photodiode testing.

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Standards quoted by this document

GB/T 2421.1-2008; GB/T 11499-2001